Model order reduction for the numerical solution of diffusive inverse problems

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- OSEM with projection ROMs





Diffusive inverse problems: motivation

- **General formulation**: determine electrical conductivity inside an object from the electromagnetic excitations and measurements on its boundary
- Controlled Source Electromagnetic Method (CSEM): low frequency EM leads to a parabolic PDE approximation of Maxwell's equations
- Electrical Impedance Tomography (EIT): zero frequency (direct current) leads to an elliptic equation for the potential



Problem formulation: EIT



- Two-dimensional problem Ω ⊂ ℝ², possibly with partial data
- Equation for electric potential u

 $\nabla \cdot (\sigma \nabla u) = 0$, in Ω

- Dirichlet data $u|_{\mathcal{B}} = \phi$ on $\mathcal{B} = \partial \Omega$
- Dirichlet-to-Neumann (DtN) map $\Lambda_{\sigma}: H^{1/2}(\mathcal{B}) \to H^{-1/2}(\mathcal{B})$

$$\Lambda_{\sigma}\phi = \left.\sigma\frac{\partial u}{\partial\nu}\right|_{\mathcal{B}}$$

Partial data:

- Split the boundary $\mathcal{B} = \mathcal{B}_A \cup \mathcal{B}_I$, accessible \mathcal{B}_A , inaccessible \mathcal{B}_I
- Similarly to the full DtN map define the partial map

$$\widetilde{\Lambda}_{\sigma}\widetilde{\phi} = \left. \left(\Lambda_{\sigma}\widetilde{\phi}
ight) \right|_{\mathcal{B}_{A}}, \text{ where supp } \widetilde{\phi} \subset \mathcal{B}_{A}$$

Partial data EIT: find σ given the map Λ_σ



Problem formulation: CSEM

• Time-dependent diffusion equation for the potential *u*:

$$u_t = \nabla \cdot (\sigma \nabla u), \quad \text{in } \Omega, \quad t > 0$$

- Also a partial data setting: $\mathcal{B} = \partial \Omega = \mathcal{B}_A \cup \mathcal{B}_I$
- Boundary conditions

$$u|_{\mathcal{B}_I}=0, \quad \left.\frac{\partial u}{\partial \nu}\right|_{\mathcal{B}_A}=0$$

Initial conditions

$$u(x,0) = \int_{\mathcal{B}_A} \phi(z) \delta(x-z) dS_z, \quad x \in \Omega \cup \mathcal{B}$$

- Measurements $y_{\sigma}(x,t) = u(x,t)$ for $x \in \mathcal{B}_A$, t > 0
- Partial data CSEM: find σ given $y_{\sigma}(x, t)$ for $x \in \mathcal{B}_A$, t > 0



Diffusive inversion stability and optimization

- Both elliptic (EIT) and parabolic (CSEM) inverse problems with boundary data are ill-posed due to the instability
- At most logarithmic stability can be achieved under certain regularity assumptions

$$\|\sigma_1 - \sigma_2\|_{\infty} \leq C \left\|\log \|d_{\sigma_1} - d_{\sigma_2}\|_{\mathcal{B}_A}\right\|^{-a},$$

where the data $d_{\sigma} = \widetilde{\Lambda}_{\sigma}$ for EIT and $d_{\sigma} = y_{\sigma}$ for CSEM

- Exponential ill-conditioning of any discretization
- Resolution is severely limited by the noise, regularization is required
- Conventional solution method: non-linear output least squares (OLS) minimization

minimize
$$\|\boldsymbol{d}^{\star} - \boldsymbol{d}_{\sigma}\|_{2}^{2} + \mu \mathcal{P}(\sigma),$$
 (1)

where d^{\star} is the measured data, $\mathcal P$ is a penalty functional and μ is a penalty parameter

 Due to ill-conditioning (1) is hard to solve, the misfit functional is non-convex, large μ may be needed, convergence is slow

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Reduced order models for inversion

- In practice a finite number *n* of data measurements is taken $M_n(d_\sigma)$
- Our approach is based on constructing a reduced order model (ROM) of size related to n that fits the measured data exactly

$$M_n(\gamma) = \mathcal{M}_n(d_\sigma),$$

here $M_n(\gamma)$ is the discrete response of the ROM parametrized by γ

• The parameters γ are chosen in such way that the mapping

$$\mathcal{Q}: \sigma
ightarrow d_{\sigma}
ightarrow \mathcal{M}_{n}(d_{\sigma})
ightarrow M_{n}(\gamma)
ightarrow \gamma$$

is an approximate identity

• The optimization problem (1) is replaced by

minimize
$$\|\gamma^{\star} - \mathcal{Q}(\sigma)\|_{2}^{2} + \mu \mathcal{P}(\sigma),$$
 (2)

where γ^{\star} is computed from data interpolation $M_n(\gamma^{\star}) = \mathcal{M}_n(d^{\star})$

 Since Q approximates identity, the misfit functional in (2) is close to quadratic and thus convex, easy to minimize

Features of inversion with ROMs

- In practice often a single Gauss-Newton iteration is enough to obtain quality reconstructions of σ
- Unlike conventional OLS approach regularization is not required for convergence, but can be added to incorporate prior information about σ
- Optimization (2) is a well-posed problem
- Where did the ill-posedness go?
- It is in the computation of the data fit

$$M_n(\gamma^{\star}) = \mathcal{M}_n(d^{\star})$$

where we assume that $M_n(\gamma^*)$ can be inverted for γ^* , i.e. we know how to solve the **discrete inverse problem**

- Discrete inversion typically takes a form of rational interpolation
- Instability of data fitting is controlled by limiting n
- Also, images can be obtained from ROM parameters γ^{*} directly without optimization using the optimal grids



Resistor networks for EIT



Circular planar graph with $n = |\mathcal{B}| = 11$ boundary nodes shown as \times

- Appropriate ROMs for EIT in 2D are resistor networks with circular planar graphs
- Network is a graph (V, E) with positive weights γ on the edges E
- Vertices V are split into interior I and boundary B
- Graph can be embedded into the unit disk D so that B are on ∂D
- Discrete derivative *D* on a graph defines a **Kirchhoff matrix**

$$K = D^T \operatorname{diag}(\gamma) D$$

• Discrete DtN map is a Schur complement

$$M_n(\gamma) = K_{\mathcal{B}\mathcal{B}} - K_{\mathcal{B}\mathcal{I}}K_{\mathcal{I}\mathcal{I}}^{-1}K_{\mathcal{I}\mathcal{B}}$$

Data measurements and fitting

- Data measured with disjoint electrode functions ψ_j, suppψ_j ⊂ B_A
- Measurement matrix $\mathcal{M}_n(\widetilde{\Lambda}_\sigma) \in \mathbb{R}^{n \times n}$ given by

$$\left[\mathcal{M}_{n}(\widetilde{\Lambda}_{\sigma})\right]_{k,j} = \int_{\mathcal{B}_{A}} \psi_{k}\widetilde{\Lambda}_{\sigma}\psi_{j}dS, \quad i \neq j$$

with the diagonal determined by current conservation

- Morrow, Ingerman, 1998: M_n(Λ̃_σ) has the properties of a DtN map of a resistor network
- Thus $M_n(\gamma^*) = \mathcal{M}_n(\widetilde{\Lambda}^*)$ for some network
- Curtis, Ingerman, Morrow, 1998: γ^{*} is uniquely recoverable from M_n(γ^{*}) iff the network's graph is well-connected and critical
- Well-connected: certain subsets of *B* can be connected with disjoint paths through the network
- Critical: removal of any edge breaks some connection
- Constructive direct method for network recovery: layer peeling



Sensitivity analysis, optimal grids and reconstructions

- Why is the mapping $\gamma = \mathcal{Q}(\sigma)$ an approximate identity?
- Can be studied by considering the **sensitivity functions**

$$\left[\frac{\delta Q}{\delta \sigma}\right]_{k} = \left[\left(\frac{\partial M_{n}(\gamma)}{\partial \gamma}\right)^{-1} \mathcal{M}_{n}\left(\frac{\delta \widetilde{\Lambda}_{\sigma}}{\delta \sigma}\right)\right]_{k},$$

where $M_n(\gamma) = \mathcal{M}_n(\widetilde{\Lambda}_{\sigma})$

- Sensitivity functions of resistor networks are localized
- Roughly, γ_k is an average of σ near the **optimal grid** node

$$x_k = \operatorname{argmax} \left[\frac{\delta \mathcal{Q}}{\delta \sigma} \right]_k$$

 Thus, γ_k may be used to define an interpolated (e.g. piecewise linear) reconstruction on the optimal grid

$$\sigma(\mathbf{x}_k) \approx \frac{\gamma_k}{\gamma_k^{(1)}},$$

where $\gamma^{(1)} = \mathcal{Q}(1)$, i.e. resistors computed for $\sigma^{(1)} \equiv 1$

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Sensitivity functions



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EIT with resistor networks

Network topologies and optimal grids



- Circular planar networks do not have to look circular
- Other topologies are better suited for partial data problem
- **Pyramidal**: if \mathcal{B}_A is simply connected
- **Two-sided**: if \mathcal{B}_A is doubly connected
- Both are wellconnected and critical
- **Top**: network topology; **Bottom**: optimal grid.

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EIT with resistor networks

Reconstructions: smooth σ , n=16



EIT with resistor networks

Reconstructions: piecewise constant σ , n=16



Newton iteration reconstructions.









Single measurement CSEM

Recall the CSEM equation

$$u_t = \nabla \cdot (\sigma \nabla u) = A_\sigma u, \quad \text{in } \Omega, \quad t > 0$$

with boundary conditions

$$u|_{\mathcal{B}_I}=0, \quad \left.\frac{\partial u}{\partial \nu}\right|_{\mathcal{B}_A}=0$$

and an initial condition

$$u(x,0) = \int_{\mathcal{B}_A} \phi(z) \delta(x-z) dS_z = \int_{\Omega} b(z) \delta(x-z) dz, \quad x \in \Omega \cup \mathcal{B},$$

with a **transducer** function b(z) satisfying supp $b \subseteq B_A$

• Let us consider a single measurement

$$y_{\sigma}(t) = \int_{\Omega} b(z) u(z,t) dz$$



Projection-based model order reduction

• Define the transfer function via Laplace transform

$$g_{\sigma}(s)=\int_{0}^{+\infty}y_{\sigma}(t)e^{-st}dt=b^{*}(sI-A_{\sigma})^{-1}b,\quad s>0$$

• Transfer function of a reduced model $A_n \in \mathbb{R}^{n \times n}$, $b_n \in \mathbb{R}^n$

$$g_n(s) = b_n^*(sI_n - A_n)^{-1}b_r$$

Projection-based model reduction

$$A_n = V^* A_\sigma V, \quad b_n = V^* b, \quad V^* V = I_n$$

• The *n* "columns" of *V* span the projection **subspace**

Choice of subspace is determined by matching conditions

$$\left[\mathcal{M}_n(\boldsymbol{y}_{\sigma})\right]_{k,j} = \left.\frac{\partial^k \boldsymbol{g}_{\sigma}}{\partial \boldsymbol{s}^k}\right|_{\boldsymbol{s}=\boldsymbol{s}_j} = \left.\frac{\partial^k \boldsymbol{g}_n}{\partial \boldsymbol{s}^k}\right|_{\boldsymbol{s}=\boldsymbol{s}_j}, \quad j=1,\ldots,m, \quad k=1,\ldots,2k_j-1$$

at interpolation nodes $s_j \in [0, +\infty)$ with

$$n = \sum_{j=1}^{m} k_j$$

Rational Krylov model order reduction

Partial fraction expansion

$$g_n(s) = \sum_{j=1}^n rac{c_j}{s+ heta_j}, \quad c_j > 0, \quad heta_j > 0,$$

with negative **poles** $-\theta_j$ and positive **residues** c_j

- Rational *g_n*, hence **rational interpolation**
- Typical choices of projection subspaces in model reduction: rational Krylov subspaces

$$\mathcal{K}_n(\mathbf{s}) = \operatorname{span}\left\{(s_j I - A_\sigma)^{-k} b \mid j = 1, \dots, m; \ k = 1, \dots, k_j\right\}$$

• Popular special cases for forward modeling: moment matching

$$\begin{aligned} \mathcal{K}_n(+\infty) &= \operatorname{span}\left\{b, A_{\sigma}b, \dots, A_{\sigma}^{n-1}b\right\} \\ \mathcal{K}_n(0) &= \operatorname{span}\left\{A_{\sigma}^{-1}b, A_{\sigma}^{-2}b, \dots, A_{\sigma}^{-n}b\right\} \end{aligned}$$

• $K_n(+\infty)$ is bad for inversion



Connection to resistor networks: S-fraction form

 Write the reduced model response as a Stieltjes continued fraction (S-fraction)



• This is a boundary response $w_1(s)$ of a second-order finite difference scheme

$$\widehat{\gamma}_{j}\left(\gamma_{j}(w_{j+1}-w_{j})-\gamma_{j-1}(w_{j}-w_{j-1})\right)-sw_{j}=0$$

- The coefficients $\gamma = \{\gamma_i, \hat{\gamma}_i\}_{i=1}^n$ are the analogue of the resistor network coefficients
- They are exactly the same for a rotationally symmetric circular network
- Once we have γ we can define

$$[M_n(\gamma)]_{k,j} = \left. \frac{\partial^k g_n(\cdot;\gamma)}{\partial s^k} \right|_{s=s_j}$$



CSEM with multiple measurements: backscattering

- To deal with multiple measurements consider many transducer functions b^α(z), α = 1,..., p with disjoint supports supp b^α ⊆ B_A
- For each $\alpha = 1, \dots, p$ perform a rational interpolation

$$M_n(\gamma^{lpha}) = \mathcal{M}_n(y^{lpha}_{\sigma})$$

and express the interpolant $g^{\alpha}_n(s;\gamma^{\alpha})$ as an S-fraction to obtain the coefficients γ^{α}

Form a joint misfit functional out of all S-fraction coefficients

$$\underset{\sigma}{\text{minimize}} \sum_{\alpha=1}^{p} \|\gamma^{\alpha} - \mathcal{Q}^{\alpha}(\sigma)\|_{2}^{2} + \mu \mathcal{P}(\sigma),$$

and solve with (a single step of) Gauss-Newton iteration

• Reminder: the mapping \mathcal{Q}^{α} is defined as a chain

$$\mathcal{Q}^{lpha}: \sigma
ightarrow y^{lpha}_{\sigma}
ightarrow \mathcal{M}_{n}(y^{lpha}_{\sigma})
ightarrow M_{n}(\gamma^{lpha})
ightarrow \gamma^{lpha}$$

• Similarly to the resistor networks we can consider the **sensitivity** functions $\left[\frac{\partial Q^{\alpha}}{\partial \sigma}\right]_{i}, j = 1, \dots, n$



Sensitivity functions





Sensitivity functions of $\widehat{\gamma}_i^{-1}$ (left) and γ_i^{-1} (right) for $i = 1, \ldots, n$ (top to bottom), n = 5 for a single transducer ($\alpha = 4$, yellow \circ) out of p = 8 (black \times). Simple Pade approximant at s = 60. Sensitivities resemble propagating spherical waves. Higher S means lower speed of propagation. Should avoid reflections from boundaries.

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CSEM with projection ROMs

Reconstructions: piecewise constant σ



Reconstuctions after a single Gauss-Newton iteration with a constant initial guess $\sigma_0 \equiv 1$. Locations of p = 8 transducers are black \times .

Conclusions and future work

Conclusions:

- A framework of ROM-based inversion for diffusive problems is proposed
- Ill-posed inverse problem is separated into two stages: ROM construction and reconstruction from ROM parameters
- The instability is confined to ROM construction, it is controlled by ROM size
- The reconstruction stage is formulated as a stable problem of minimizing the ROM parameter misfit
- The parameters are chosen so that they depend almost linearly on the unknown PDE coefficient
- Thus the ROM parameter misfit minimization is close to quadratic and can be solved with a single step of Gauss-Newton iteration

Future work:

- EIT with resistor networks currently works in 2D or for limited subsets of 3D data, a full 3D approach is yet to be developed
- ROM-based CSEM inversion works in any dimension, but uses only the backscattering data

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